

12500 TI Boulevard, MS 8640, Dallas, Texas 75243

PCN# 20180925002.1A Qualification of TI Malaysia as an additional Assembly Site for select devices Change Notification / Sample Request

Date: October 16, 2018 **To:** MOUSER PCN

Dear Customer:

Revision A is to add the affected customer device list under Page 2 of this PCN letter. We apologize for any inconvenience this may have caused.

This is an announcement of a change to a device that is currently offered by Texas Instruments. The details of this change are on the following pages.

We request you acknowledge receipt of this notification within **30** days of the date of this notice. Lack of acknowledgement of this notice within 30 days constitutes acceptance of the change. If you require samples or additional data to support your evaluation, please request within 30 days.

The proposed first ship date is indicated on page 3 of this notification, unless customer agreement has been reached on an earlier implementation of the change.

This notice does not change the end-of-life status of any product. Should product affected be on a previously issued product withdrawal/discontinuance notice, this notification does not extend the life of that product or change the life time buy offering/discontinuance plan.

For questions regarding this notice, contact your local Field Sales Representative or the PCN Manager (PCN ww admin_team@list.ti.com).

Sincerely, PCN Team SC Business Services

20180925002A Attachment: 1

Products Affected:

The devices listed on this page are a subset of the complete list of affected devices. According to our records, these are the devices that you have purchased within the past twenty-four (24) months. The corresponding customer part number is also listed, if available.

DEVICE	CUSTOMER PART NUMBER
UC2638N	null
UC2855BN	null
UC2875N	null
UC2879N	null
UC3638N	null
UC3855BN	null
UC3875N	null
UC3876N	null
UC3879N	null
UCC28500N	null
UCC2895N	null
UCC38500N	null
UCC38501N	null
UCC38502N	null
UCC3895N	null

Technical details of this Product Change follow on the next page(s).

DCN	Numl	hori	20180925002.1A PCN Date: Oct 1					Oct 16, 2018						
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Title	e : : : : : : : : : : : : : : : : : : :				onai .					ices				
Customer Contact: PCN Manager D			De			Quality S								
Prop	osed	1 st Ship Dat	:e:	Jan 05,	20	19	Estima Availa		Sample y:			ate Provided at Sample quest		
	ige Ty													
Assembly Site			Ц	_	sign			ļĻ	╝	Wafer Bum				
		nbly Process				ta Shee			Ļ	Wafer Bump Material				
Assembly Materials Mechanical Specification			_	Part number change			┽	Wafer Bump Process Wafer Fab Site						
		ng/Shipping/I			Н		st Proce	200		╁	╡	Wafer Fab Materials		
	I ackii	пд/этпррппд/т	Label	iiig		103	SC 1 TOCK	.33		╅	┪	Wafer Fab I		
						P	CN De	etai	s	- -			. 00000	
Desc	riptio	n of Change	2:				<u> </u>							
Site f	Texas Instruments Incorporated is announcing the qualification TI Malaysia as Additional Assembly Site for select devices listed in the "Product Affected" Section. Current assembly sites and Material differences are as follows.													
				Ass		bly S	Site	As	sembly C		ntı	ry Asse	embly Site	
		embly Site				igin			Code			Cha	City	
		nip Technolog Malaysia	ly			<u>LP</u> LA			THA MYS				choengsao Ila Lumpur	
Mate		Differences:				LA			1413			Ruu	ia Euripai	
Grou	Group 1 Device:													
			Mic	rochip	Te	chno	ology		TI Mal	ays	sia	1		
Мо	ount C	Compound	142010008					4147858						
№	1old co	ompound		1410	0020	081		4211880						
	Lead	l finish		Ma	tte S	Sn		NiPdAu						
Grou	Group 2 Device:													
	Microchip Technolog			ology		TI Mal	ays	sia						
Mo	ount (Compound	-						4147858					
		ompound 141002081				4211880								
	141002001 4211000													
Reason for Change:														
Continuity of supply.														
Anticipated impact on Form, Fit, Function, Quality or Reliability (positive / negative):														
None														
Antic	cipate	ed impact or	Mat	terial D)ecl	arat	ion							
Material Declaration production dat release. Upon			n data Upon p from th meeting	and rodu ie <u>TI</u> g cur	will be ava ction relea <u>Eco-Info v</u> rent regula	ilal ise <u>veb</u>	ole the sit	following the revised reperture repe	ports can be no impact to the					
		o product ic		£! L!		14.			-i- DCN-					

Assembly Site		
Microchip Technology	Assembly Site Origin (22L)	ASO: ALP
TI Malaysia	Assembly Site Origin (22L)	ASO: MLA

Sample product shipping label (not actual product label)





(1P) \$N74L\$07N\$R (Q) 2000 (D) 0336 (31T)LOT: 3959047MLA (4W) TKY(1T) 7523483\$I2 (P) (2P) REV: (V) 0033317 (20L) CSO: SHE (21L) CCO:USA (22L) ASP: MLA (23L) ACO: MYS

Group 1 Product Affected:

	UC2875N	UC3875N	UC3876N
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Group 2 Product Affected:

UC2638N	UC3638N	UC3879N	UCC38502N
UC2855BN	UC3638NG4	UCC28500N	UCC38502NG4
UC2875NG4	UC3855BN	UCC2895N	UCC3895N
UC2879N	UC3855BNG4	UCC38500N	UCC3895NG4
UC2879NG4	UC3875NG4	UCC38501N	

Qualification Report

MMT Offload Qualification for PDIP 20N devices

Approve Date 25-May-2018

Product Attributes

Attributes	Qual Device: <u>UC3875N</u>	Qual Device: <u>UCC38501N</u>	QBS Package Reference: <u>SN74HCT540N</u>	QBS Package Reference: TPA3122D2N
Assembly Site	MLA	MLA	MLA	MLA
Package Family	PDIP	PDIP	PDIP	PDIP
Flammability Rating	UL 94 V-0	UL 94 V-0	UL 94 V-0	UL 94 V-0
Wafer Fab Supplier	SFAB	SFAB	SFAB	UMC FAB8AB
Wafer Fab Process	JI_PWR2	IMP-PWR2	74HC-NONEPI	LBC5X

⁻ QBS: Qual By Similarity

Qualification Results

Data Displayed as: Number of lots / Total sample size / Total failed

Туре	Test Name / Condition	Duration	Qual Device: <u>UC3875N</u>	Qual Device: <u>UCC38501N</u>	QBS Package Reference: SN74HCT540N	QBS Package Reference: <u>TPA3122D2N</u>
AC	Autoclave 121C	96 Hours	3/231/0	3/231/0	3/231/0	3/231/0
FLAM	Flammability (UL 94V-0)	-	-	-	3/15/0	-

⁻ Qual Devices UC3875N and UCC38501N are qualified at Not Classified

Туре	Test Name / Condition	Duration	Qual Device: <u>UC3875N</u>	Qual Device: <u>UCC38501N</u>	QBS Package Reference: <u>SN74HCT540N</u>	QBS Package Reference: <u>TPA3122D2N</u>
HTSL	High Temp Storage Bake 170C	420 Hours	3/231/0	3/231/0	3/231/0	3/231/0
LI	Lead Fatigue	Leads	-	-	3/45/0	3/45/0
LI	Lead Pull to Destruction	Leads	-	-	3/180/0	3/180/0
MQ	Manufacturability (Assembly)	(per mfg. Site specification)	Pass	Pass	Pass	Pass
PKG	Lead Finish Adhesion	Leads	-	-	2/30/0	3/45/0
SD	Solderability	8 Hours Steam Age	3/30/0	3/30/0	3/66/0	3/66/0
TC	Temperature Cycle, - 65/150C	500 Cycles	3/231/0	3/231/0	3/231/0	3/231/0

- Preconditioning was performed for Autoclave, Unbiased HAST, THB/Biased HAST, Temperature Cycle, Thermal Shock, and HTSL, as applicable
- The following are equivalent HTOL options based on an activation energy of 0.7eV : 125C/1k Hours, 140C/480 Hours, 150C/300 Hours, and 155C/240 Hours
- The following are equivalent HTSL options based on an activation energy of 0.7eV : 150C/1k Hours, and 170C/420 Hours
- The following are equivalent Temp Cycle options per JESD47 : -55C/125C/700 Cycles and -65C/150C/500 Cycles Quality and Environmental data is available at Tl's external Web site: http://www.ti.com/

Green/Pb-free Status:

Qualified Pb-Free(SMT) and Green

THIS INFORMATION RELATING TO QUALITY AND RELIABILITY IS PROVIDED "AS IS." Product information detailed in this report may not accurately reflect Tl's current product materials, processes and testing used in the construction of the TI products. Customers are solely responsible to conduct sufficient engineering and additional qualification testing to determine whether a device is suitable for use in their applications. Using TI products outside limits stated in Tl's datasheet may void Tl's warranty. See Tl's Terms of Sale at "http://www.ti.com/lsds/ti/legal/termsofsale.page"

For questions regarding this notice, e-mails can be sent to the regional contacts shown below or your local Field Sales Representative.

Location	E-Mail
USA	PCNAmericasContact@list.ti.com
Europe	PCNEuropeContact@list.ti.com
Asia Pacific	PCNAsiaContact@list.ti.com
Japan	PCNJapanContact@list.ti.com